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Connecting Mission Profiles and Radiation Vulnerability Assessments

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Design

RVA

Prototype

Rad-Hard

Testing



Expected Users of Radiation Vulnerability Assessment



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- Teams most likely to:
 - Use commercial-off-the-shelf (COTS) components
 - Lack (at least initially) radiation effects experts
- Rad-hardened components are more expensive than their non-rad-hardened counterparts
- These groups include:
 - Small satellite (e.g., CubeSat) teams
 - Academic design teams
 - Satellite startups



VS.

- Renesas Electronics HS1-82C54RH-Q: Rad-hard Programmable Timer Price: ~\$3,100 Lead Time: 21 Weeks and 2 Days
- Intel 8254: Nonrad-hard Programmable Timer **Price: ~ \$7.00** Lead Time: In Stock

Assessing Radiation Vulnerability Assessment



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User-Input

- Spacecraft's mission environment
- Spacecraft's electronic part portfolio



Radiation Vulnerability Assessment

 Model of radiationinduced fault propagation through spacecraft's electronic parts



Radiation Fault Propagation Model Template



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SEAM Fault Model Templates

- Part type models
- Contains radiation-induced faults for typical part types

SEAM SysML Model

 User can interconnect part type models according to their design and complete system architectural models in SEAM



Interfacing RGENTIC and SEAM



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RGENTIC

 Creates a part list associating components with rad risks based on userspecified environment Transferred via Config. File



SEAM

 Allows user to create fault propagation model through spacecraft system through part list matching



RGENTIC's Part Type Families



- Families Present (66 total part types):
 - Clocks/Timing (4 part types)
 - Digital (5 part types)
 - Discrete (4 part types)
 - Discrete Power (7 part types)
 - Discrete RF (8 part types)
 - Embedded (4 part types)
 - Interfaces (6 part types)
 - Linear (5 part types)
 - Logic (2 part types)
 - Memory (4 part types)
 - Mixed Signal (5 part types)
 - Opto-Electronics (4 part types)
 - Power Hybrid (4 part types)
 - Sensors (4 part types)

- Radiation Concerns Present:
 - Single Event Latch-up
 - Single Event Burnout
 - Single Event Transient
 - Single Event Function Interrupt
 - Single Event Gate-Rupture
 - Single Event Upset
 - Multiple Bit Upset
 - Total Ionizing Dose
 - Displacement Damage Dose



RGENTIC: Radiation GuidelinEs for Notional Threat Identification and Classification



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- Free platform developed at NASA Goddard Space Flight Center (GSFC)
- Provides guidance on assessing radhardness of EEE components
- RGENTIC Process:
 - User Mission
 - Environment Comparison
 - Device Response
 - Guidelines

🞯 R-GENTIC

Tool Guide:

This tool is meant to be used as guidance for understanding the radiation risks that apply to a specific set of circumstances, not to replace modeling one's own environment or replacing the need to test a device. When used from start to finish you can get guidelines to help mitigate radiation effects and understand where you can avoid risks, based on simplified inputs, for a parts list in question.

Each Navigation Tab is a step in the process:

1. User Mission - Begin with selecting the options that apply to you for an intended mission, each input will directly impact the output of the tool that is to follow. At any time, you can choose to begin again, or follow the path for a new mission design under question. By selecting a mission class, lifetime, orbit, and architecture you are returned an environment severity with contributions and the EEE threats the tool will focus on.

2. Environment Comparison - Using the inputs from section 1, the tool displays past mission modeling efforts that have been done. It returns the details of a mission that has been calculated to be close to yours when normalized for one year. This panel allows selection of multiple missions to compare and explore. It should be noted that the Solar cycle has an impact on the dose based on the launch year, and the normalization is for approximation. This piece of the tool is to show how shielding can be used to mitigate dose levels, and how mission characteristics impact your SEE concerns. Two plots are available, the TID vs. shielding depth curve and the GCR spectra. The tool also returns data tables for all plots rendered.

3. Device Response -Using the top level selections from section 1, the device susceptibility and basic radiation concerns are called out when the user inputs the device information. Here the tool returns examples of the most prevalent radiation concerns through plots and references of similar components where possible.

4. Guidelines -The final step captures radiation line of questioning that is tailored to the user inputs, the major concerns are clarified and the user is presented with mitigation strategies. You can also see a listing of class guidelines with respect to radiation using the dropdown. In an effort to document failure modes and reduce the threat/risk to the system from a radiation standpoint, a line of risk pre and post mitigation is returned. This output can be saved and added to a table in the summary.

Due to the fact that radiation effects are application specific, this guidance is notional, generalizations cannot cover the entire state-space and the user will benefit from a more detailed analysis.

Proceed with Notional Guidance

https://vanguard.isde.vanderbilt.edu/RGentic/





Step 2: Radiation Environment Comparison







Step 3: Mission-Specific Device Vulnerability



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- Input device type so RGENTIC can identify radiation concerns
- Device susceptibility to various potential radiation concerns are shown
- Only generic part-types considered

Device: Data: Assign a Reference Designator or NASA Radiation Report Resource Links (first place to look for Unique ID your part number): NASA GSFC Radiation Effects and Analysis Group DUT1 **PMPedia** Family: Function: Opto-Discrete For Your Device Inputs of: electronics LED **Opto-electronics Discrete LED** Mission specific Radiation Concerns by Family are: Enter Device Process if Known (for documentation) TID, DDD, SET, SEB, SEGR N/A Typical responses: Criticality: Low (Device degradation/loss of functionality acceptable) Tend to be significantly impacted by DDD, which takes form in CTR degradation and/or power output for LEDs. Can exhibit transients as well Medium (Some degradation or depending on application. upsets acceptable, but no loss of device) High (Device must perform within specifications for successful mission)

How do Similar Devices React?



Step 4: Risk Mitigation Guidelines



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- Top-left box:
 - Typical line of radiation
 questioning for Family of device
 - Device-specific information
 given beneath
- Lower-left box:
 - Recommendations based on:
 - Part's criticality
 - Environment's severity
 - Mission class

What should you do to bring down the risk?

The typical line of radiation questioning for: Optoelectronics N/A Discrete LED with regard to TID, DDD, SET, SEB, SEGR

No concern for SEB. SETs are not a concern. No concern for TID. No concern for SEGR. Can the design deal with reduced optical output?

Criticality vs. Environment:

Level 1 or 2, rad hard suggested. Full upscreening for COTS. Fault tolerant designs for COTS.

NASA Class A Guidelines:

Show 10 V entries

Components shall be radiation-hardened with guarantees for TID, DDD, and SEE performance designed to meet mission requirements for the specified orbit/trajectory. All required radiation testing (TID, DDD, and/or SEE) shall be on the flight lot and conducted at the part level. Fault-tolerant designs required for COTS parts. Impacts constrained to cost and schedule.

Save to Summary Sheet

Mission

Single

with

spacecraft,

redundancy

LEO

(Polar)

Architecture

Add my next part

Environment

Discrete

LED

Medium

DUT1

Severity

High

Your tailored table s

),	Considered for Medium criticality component on a Single spacecraft, with redundancy				
No out?	Your Part	Radiation concerns	Greatest System Rad Concern	As-is Risk	Post Rec Risk
	DUT1	TID, DDD, SET, SEB, SEGR	Degradation & Single Event	Medium	Low
t		Recomme	endation and Gui	delines:	
	Most LEDs have slow on/off times making Single events negligible on the power output of the device.				
nts , part	Please send questions and feedback to: michael.j.campola@nasa.gov Additionally a Model Based Mission Assurance Tool Can extend this analysis - SEAM				
	Addition		analysis - SEAM		tena tris
± Dor	Addition	ry Sheet 🛃	analysis - SEAM	Sheet	tena this
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Dor umman Dund	wnload Summa y of saved r	ry Sheet 🛃	analysis - SEAM Download JSON fmt S DWS: Search:	Sheet	tend this

Degradation

Medium Low

& Single

Event



SEAM: Systems Engineering and Assurance Modeling



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- Free platform used to evaluate any spacecraft system
- Useful for radiation fault modeling and radiation case development
- Applications with short development timeframes and COTS usage



https://modelbasedassurance.org/



- SEAM incorporates SysML internal block diagrams
- SEAM has the following capabilities:
 - Assessment of radiation performance of a spacecraft without relying on intensive radiation testing campaigns
 - Does not require extensive physical knowledge of the electronic components



SEAM Templates Based on RGENTIC Part Categories



- Discrete LED Annotation Each part Main radiation concerns in Discrete LEDs: DDD, Note: Degraded Brightness is a decrease in output light. type · Possible input failure labels: Degraded Bias, Incorrect Bias reviewed by Date created: 5/6/2020 by KLR radiation Date updated: 5/13/2020 by KLR Date checked: experts Gradual Power Change **Degraded Brightness** DDD **Output Light** Power **Power Port** Fault Failure Label Anomaly
- SEAM model of Discrete LED shown in the editor canvas.
- Engineers can choose modeling elements from the model parts panel on the same page as this figure.
- SEAM allows users to create project libraries for both components and failure labels.

SEAM Output







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Sensor Part-Type Output from SEAM





Systems Engineering and Assurance Modeling (SEAM): A Web-Based Solution for Integrated Mission Assurance, Kaitlyn Ryder et. al, Electronics and Energetics, 2021





- Radiation vulnerability assessment can reduce total time and money required to complete a spacecraft system
- RGENTIC and SEAM are two tools that provide early radiation assessment
- RGENTIC helps users identify radiation vulnerabilities based on mission parameters
- SEAM allows users to build a model of the radiation fault propagation in a system and a radiation assurance case